

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/661,503	HIKAWA ET AL.	
Examiner	Art Unit	
Philip C. Lee	2152	

	SEARCHED		
Class	Subclass	Date	Examiner
709	224	12/16/2007	PL
717	102	12/16/2007	R
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY))
	DATE	EXMR
keywords search in 709/224, 717/102 in EAST	12/16/2007	PL
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